IEC/IEEE 60802 to IECEE Reference Model

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Mission and Scope of IEC/IEEE 60802 and the relation to IECEE conformance test

IA profile is intended to state:
- the used standards
- the mandatory to be supported features out of these standards
- the optional to be supported features out of these standards
- the to be excluded features out of these standards
- the mandatory quantities for the mandatory and optional features
- the managed objects assigned to the mandatory and optional features and their be supported values and value ranges
- the MIBs and/or YANG modules representing these managed objects
- the Device Description content to specify the features and quantities a dedicated device is supporting

IECEE creates test specification to verify all mandatory and optional features of the IEC/IEEE 60802 with the values from the “Device Description”

Device supplier provides a “Device Description” to specify the features this device is supporting.
Questions?